


Search Notes 	Application/Control No. 10804722	Applicant(s)/Patent Under Reexamination CHOI ET AL.
	Examiner Mandeville, Jason M	Art Unit 2629

SEARCHED			
Class	Subclass	Date	Examiner
345	76-84, 690, 694-695	17 October 2007	Jason Mandeville
313	483-512	17 October 2007	Jason Mandeville
315	169.1-169.3	17 October 2007	Jason Mandeville
345	76-84, 690, 694-695	16 April 2008	Jason Mandeville
313	483-512	16 April 2008	Jason Mandeville
315	169.1-169.3	16 April 2008	Jason Mandeville
345	76-78, 82-84, 87-89, 690, 694-695	11/04/2008	Jason Mandeville
313	483-512	11/04/2008	Jason Mandeville
315	169.1-169.3	11/04/2008	Jason Mandeville
345	76-78, 82-84, 87-89, 690, 694-695	14 May 2009	Jason Mandeville
313	483-512	14 May 2009	Jason Mandeville
315	169.1-169.3	14 May 2009	Jason Mandeville

SEARCH NOTES		
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Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	17 October 2007	Jason Mandeville
Inventor Search	17 October 2007	Jason Mandeville
Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	16 April 2008	Jason Mandeville
Inventor Search	16 April 2008	Jason Mandeville

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Inventor Search	14 May 2009	Jason Mandeville

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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